

APR 10 2006 PAGE 02/07

RESPONSE UNDER 37 C.F.R. § 1.116
EXPEDITING PROCEDURE
EXAMINING GROUP 2800

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Schneegans, et al. Docket No.: 2001 P 17353 US
Serial No.: 10/826,954 Art Unit: 2829
Filed: April 15, 2004 Examiner: Nguyen, Jimmy
For: Probe Needle for Testing Semiconductor Chips and Method for Producing
Said Probe Needle

OK
encl
to PW
ff
4/10/06
Mail Stop: After Final
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE UNDER 37 CFR § 1.116

Dear Sir:

Applicant respectfully submits the following remarks in response to Examiner's Office Action dated February 10, 2006, which Action was made final. Applicant respectfully requests that these remarks be entered in pursuant to the provisions of 37 CFR § 1.116, and respectfully requests reconsideration of the pending claims.